

IN THE CLAIMS

1. (Original) A test system which performs electrical tests on semiconductor chips formed on a semiconductor wafer, comprising:

a probe card which is provided with conductive needles in alignment with the placement of electrode pads in the semiconductor chips and connected to a test circuit;

a test circuit which is placed on said probe card and conducts tests on the semiconductor chips, based on a program; and

a control device which writes a program in said test circuit and stores therein a test result outputted from said test circuit.

Claims 2-24 (Canceled)